

LISTING OF CLAIMS:

Please amend the claims as follows:

1. (Currently Amended) A film (1, 3, 6, 7, 8, 9), in particular a stamping or laminating film, which includes at least one component produced using organic semiconductor technology, in particular one or more organic field effect transistors, wherein the component includes a plurality of layers and wherein the plurality of layers include electrical functional layers,

~~characterised in that~~

wherein one or more layers of the component are provided with a spatial structuring by means of thermal replication or UV replication, wherein at least one functional layer is partially completely severed in the region of the spatial structuring.

2. (Currently Amended) A film (1, 3, 6, 7, 8, 9) as set forth in claim 1, wherein ~~characterised in that~~ the film is a stamping or laminating film.

3. (Currently Amended) A film (1, 3, 6, 7, 8, 9) as set forth in claim 2, wherein ~~characterised in that~~ the stamping or laminating film ~~has~~ comprises:

a carrier film (11, 61, 71, 81),

at least one layer (16, 67, 76, 88) comprising an organic semiconductor element, in particular polythiophene,

at least one layer (15, 65, 75, 87) comprising an electrically insulating material, and two or more layers (14, 17, 19, 64, 66, 74, 77, 86, 89) which are shaped in a pattern configuration in region-wise manner and which comprise an electrically conductive material.

4. (Currently Amended) A film (1, 3, 6, 7, 8, 9) as set forth in claim 3, wherein characterised in that the electrically conductive layers (14, 17, 19, 64, 66, 74, 77, 86, 89) comprise an organic conductive material, in particular polyaniline or polypyrrole.

5. (Currently Amended) A film (1, 3, 6, 7, 8, 9) as set forth in claim 3, wherein or claim 4 characterised in that the electrically insulating layer (15, 65, 75, 87) comprises an organic insulation material, in particular polyvinylphenol.

6. (Currently Amended) A film (1, 3, 6, 7, 8, 9) as set forth in claim 2, wherein one of claims 2 through 5 characterised in that the film is a stamping film which has a carrier film (11) and a transfer layer portion (2) which is applied to the carrier film (11) and which is releasable from the carrier film (11).

7. (Currently Amended) A film (1, 3, 6, 7, 8, 9) as set forth in claim 6, wherein characterised in that the stamping film has a release layer (12, 62, 72, 82) and an adhesive layer (20, 69, 79, 97).

8. (Currently Amended) A film (1, 3, 6, 7, 8, 9) as set forth in claim 2, wherein ~~one of claims 2 through 7 characterised in that~~ the stamping or laminating film has one or more lacquer layers (13, 18, 63, 68, 73, 78, 84, 90) adjoining functional polymer layers.

9. (Currently Amended) A film (1, 3, 6, 7, 8, 9) as set forth in claim 3, wherein ~~characterised in that~~ the electrically conductive layers, the layer comprising a semiconductor material and the layer comprising an electrically insulating material are transparent.

10. (Currently Amended) A film as set forth in claim 1, wherein ~~characterised in that~~ the film is a film element (2) which has a layer comprising:
an organic semiconductor material (16), in particular polythiophene,
a layer (15) comprising an electrically insulating material, and
two or more layers which comprise an electrically conductive material (14, 17, 19) and which are shaped in a pattern configuration in region-wise manner.

11. (Currently Amended) A film as set forth in claim 10, wherein ~~characterised in that~~ the film (2) is a film element which is applied to a substrate by means of a stamping or laminating film (1), ~~in particular as set forth in one of claims 2 through 9.~~

12. (Currently Amended) A film (8) as set forth in claim 1, wherein ~~characterised in that one of the preceding claims characterised in that~~ an electrical functionality, in particular that

of at least one electrical component produced using organic semiconductor technology, is combined with optical features.

13. (Currently Amended) A film (8) as set forth in claim 12, wherein ~~characterised in that~~ the film has a spatial structure (47) which is shaped between layers of the film and which on the one hand structures in a pattern configuration a layer (46) of the electronic component produced using organic semiconductor technology and on the other hand generates an optical-diffraction effect as an optical feature.

14. (Currently Amended) A film as set forth in claim 13, wherein ~~characterised in that~~ the spatial structure (47) is formed by a superimposition of a microstructure and a macrostructure, wherein the macrostructure serves for the patterned structuring of a layer (46) of the electronic component produced using organic semiconductor technology and the microstructure serves for the generation of the optical feature.

15. (Currently Amended) A film (8) as set forth in claim 1, wherein ~~one of the preceding claims characterised in that~~ the film has a holographic-optical or diffractive layer (83, 84, 90, 91).

16. (Currently Amended) A film (8) as set forth in claim 1, wherein ~~one of the preceding claims characterised in that~~ the film has a thin-film layer sequence (94, 95).

17. (Currently Amended) A film as set forth in claim 1, wherein ~~one of the preceding claims characterised in that~~ the film has a decoration layer.

18. (Currently Amended) A film ~~(8)~~ as set forth in claim 1, wherein ~~one of the preceding claims characterised in that~~ the film ~~(8)~~ has two or more mutually superposed layers ~~(83, 84, 90, 91, 94, 95)~~ which generate an optical security feature, wherein one or more functional layers ~~(86, 87, 88, 89)~~ of the electronic component produced using organic semiconductor technology are arranged between such optically active layers.

19. (Currently Amended) A film as set forth in claim 1, wherein ~~one of the preceding claims characterised in that~~ the film is used as a security element.

20. (Currently Amended) A process for the production of a film ~~(1, 3, 6, 7, 8, 9)~~ as set forth in claim 1, wherein ~~characterised in that~~ structuring of one or more layers ~~(43, 49, 50)~~ of the at least one component produced using organic semiconductor technology is effected by thermal replication or UV replication.

21. (Currently Amended) A process as set forth in claim 20, wherein ~~characterised in that~~ replicated into the layer ~~(42)~~ to be replicated is a spatial structure whose structure depth is greater than or equal to the thickness of the layer ~~(42)~~ to be replicated, so that the layer to be replicated is completely severed in part by the replication operation and an electrical functional

layer (43) which is structured in a pattern configuration in accordance with the spatial structure is formed.

22. (Currently Amended) A process as set forth in claim 21, wherein characterised in that such a spatial structure is replicated in an electrode layer comprising an electrically conductive material and then an electrical functional layer comprising a non-conducting or semiconducting material is applied to said layer.

23. (Currently Amended) A process as set forth in claim 20, wherein characterised in that replicated into the layer (42) to be replicated is a spatial structure whose structure depth is less than the thickness of the layer (48) to be replicated.

24. (Currently Amended) A process as set forth in claim 23, wherein characterised in that there is applied to the replicated layer (46) an electrical functional layer (49) of a material which upon hardening experiences a pre-defined reduction in volume, and that said material is applied to the replicated layer (46) in an application amount with which upon hardening a functional layer (49) which is structured in a pattern configuration in accordance with the replicated structure remains by virtue of the shrinkage in volume.

25. (Currently Amended) A process as set forth in claim 24, wherein characterised in that the functional layer comprises an UV-hardenable material.

26. (Currently Amended) A process as set forth in claim 23, wherein ~~characterised in that~~ an electrical functional layer (50) is applied to the replicated layer (46) and that the electrical functional layer is then removed, in particular by etching, to a depth such that there remains a functional layer (50) which is structured in a pattern configuration in accordance with the replicated structure.

27. (Currently Amended) A process as set forth in claim 23, wherein ~~one of claims 23 through 26 characterised in that~~ the spatial structure is replicated in an electrical functional layer comprising a non-conducting or semiconducting material and then an electrode layer comprising a conductive material is applied to said layer.

28. (Currently Amended) A process for the production of a film as set forth in claim 1, wherein ~~in particular a process as set forth in claim 20, characterised in that~~ all or one or more electrode, insulation and semiconducting layers which are required for the function of the at least one component produced using organic semiconductor technology are introduced into a film structure over the entire surface area or part of the surface area by printing processes.

29. (Currently Amended) A process as set forth in claim 20, wherein ~~one of claims 20 through 28 characterised in that~~ an electrical functionality, in particular one or more components produced using organic semiconductor technology, and an optical functionality, in particular diffractive-optical structures, are produced by a replication operation.